Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination
10/764,481	HIYAMA ET AL.
Examiner	Art Unit

Mark A. Mais

2616

SEARCHED					
Class	Subclass	Date	Examiner		
370	310 328 329	6/16/2007	MAM		
	331 338 351				
	352 353 389				
	392 401 469				
	474 475 476				
7					

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
L					

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
See Inventorship Search	6/16/2007	MAM		
See Attached Electronic Search	6/16/2007	MAM		
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